

## EMIPAK-2B PressFit Power Module Three Levels Half-Bridge Inverter Stage, 75 A



**EMIPAK-2B**  
(package example)

**FEATURES**

- Trench IGBT technology
- FRED Pt® clamping diodes
- PressFit pins technology
- Exposed Al<sub>2</sub>O<sub>3</sub> substrate with low thermal resistance
- Short circuit rated
- Square RBSOA
- Integrated thermistor
- Low internal inductances
- Low switching loss
- UL approved file E78996
- Material categorization: for definitions of compliance please see [www.vishay.com/doc?99912](http://www.vishay.com/doc?99912)



**RoHS**  
COMPLIANT

**PRODUCT SUMMARY**

Q1 - Q4 IGBT STAGE	
$V_{CES}$	600 V
$V_{CE(ON)}$ typical at $I_C = 75$ A	1.7 V
$I_C$ at $T_C = 89$ °C	75 A
Q2 - Q3 IGBT STAGE	
$V_{CES}$	600 V
$V_{CE(ON)}$ typical at $I_C = 75$ A	1.56 V
$I_C$ at $T_C = 122$ °C	75 A
Speed	8 kHz to 30 kHz
Package	EMIPAK-2B
Circuit	3-levels half bridge inverter stage

**DESCRIPTION**

VS-ETF075Y60U is an integrated solution for a multi level inverter stage in a single package. The EMIPAK-2B package is easy to use thanks to the PressFit pins and the exposed substrate provides improved thermal performance. The optimized layout also helps to minimize stray parameters, allowing for better EMI performance.

**ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS
Operating junction temperature	$T_J$		175	°C
Storage temperature range	$T_{Stg}$		-40 to +150	
RMS isolation voltage	$V_{ISOL}$	$T_J = 25$ °C, all terminals shorted, $f = 50$ Hz, $t = 1$ s	3500	V
<b>Q1 - Q4 IGBT</b>				
Collector to emitter voltage	$V_{CES}$		600	V
Gate to emitter voltage	$V_{GES}$		20	
Pulsed collector current	$I_{CM}$		200	A
Clamped inductive load current	$I_{LM}^{(1)}$		200	
Continuous collector current	$I_C$	$T_C = 25$ °C	109	A
		$T_C = 80$ °C	80	
		$T_{SINK} = 80$ °C	40	
Power dissipation	$P_D$	$T_C = 25$ °C	294	W
		$T_C = 80$ °C	186	
<b>Q2 - Q3 IGBT</b>				
Collector to emitter voltage	$V_{CES}$		600	V
Gate to emitter voltage	$V_{GES}$		20	
Pulsed collector current	$I_{CM}$		250	A
Clamped inductive load current	$I_{LM}^{(1)}$		250	
Continuous collector current	$I_C$	$T_C = 25$ °C	154	A
		$T_C = 80$ °C	113	
		$T_{SINK} = 80$ °C	50	
Power dissipation	$P_D$	$T_C = 25$ °C	405	W
		$T_C = 80$ °C	257	



<b>ABSOLUTE MAXIMUM RATINGS</b>				
<b>D5 - D6 CLAMPING DIODE</b>				
Repetitive peak reverse voltage	$V_{RRM}$		600	V
Single pulse forward current	$I_{FSM}$	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	270	A
Diode continuous forward current	$I_F$	$T_C = 25\text{ }^\circ\text{C}$	78	
		$T_C = 80\text{ }^\circ\text{C}$	55	
		$T_{SINK} = 80\text{ }^\circ\text{C}$	28	
Power dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	174	W
		$T_C = 80\text{ }^\circ\text{C}$	110	
<b>D1 - D2 - D3 - D4 AP DIODE</b>				
Single pulse forward current	$I_{FSM}$	10 ms sine or 6 ms rectangular pulse, $T_J = 25\text{ }^\circ\text{C}$	250	A
Diode continuous forward current	$I_F$	$T_C = 25\text{ }^\circ\text{C}$	72	
		$T_C = 80\text{ }^\circ\text{C}$	70	
		$T_{SINK} = 80\text{ }^\circ\text{C}$	31	
Power dissipation	$P_D$	$T_C = 25\text{ }^\circ\text{C}$	107	W
		$T_C = 80\text{ }^\circ\text{C}$	68	

**Notes**

- Absolute Maximum Ratings indicate sustained limits beyond which damage to the device may occur.
- (1)  $V_{CC} = 300\text{ V}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\text{ }\mu\text{H}$ ,  $R_g = 4.7\text{ }\Omega$ ,  $T_J = 175\text{ }^\circ\text{C}$

<b>ELECTRICAL SPECIFICATIONS (<math>T_J = 25\text{ }^\circ\text{C}</math> unless otherwise noted)</b>						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q1 - Q4 IGBT</b>						
Collector to emitter breakdown voltage	$BV_{CES}$	$V_{GE} = 0\text{ V}$ , $I_C = 100\text{ }\mu\text{A}$	600	-	-	V
Collector to emitter voltage	$V_{CE(ON)}$	$V_{GE} = 15\text{ V}$ , $I_C = 60\text{ A}$	-	1.57	1.8	V
		$V_{GE} = 15\text{ V}$ , $I_C = 75\text{ A}$	-	1.7	1.93	
		$V_{GE} = 15\text{ V}$ , $I_C = 60\text{ A}$ , $T_J = 125\text{ }^\circ\text{C}$	-	1.7	-	
		$V_{GE} = 15\text{ V}$ , $I_C = 75\text{ A}$ , $T_J = 125\text{ }^\circ\text{C}$	-	1.86	-	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}$ , $I_C = 2.1\text{ mA}$	3.6	5.6	7.1	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}$ , $I_C = 1\text{ mA}$ ( $25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$ )	-	-12	-	mV/ $^\circ\text{C}$
Forward transconductance	$g_{fe}$	$V_{CE} = 20\text{ V}$ , $I_C = 75\text{ A}$	-	51	-	S
Transfer characteristics	$V_{GE}$	$V_{CE} = 20\text{ V}$ , $I_C = 75\text{ A}$	-	9.6	-	V
Zero gate voltage collector current	$I_{CES}$	$V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$	-	0.0002	0.1	mA
		$V_{GE} = 0\text{ V}$ , $V_{CE} = 600\text{ V}$ , $T_J = 125\text{ }^\circ\text{C}$	-	0.01	-	
Gate to emitter leakage current	$I_{GES}$	$V_{GE} = \pm 20\text{ V}$ , $V_{CE} = 0\text{ V}$	-	-	$\pm 200$	nA



<b>ELECTRICAL SPECIFICATIONS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q2 - Q3 IGBT</b>						
Collector to emitter breakdown voltage	$BV_{CES}$	$V_{GE} = 0\text{ V}, I_C = 500\text{ }\mu\text{A}$	600	-	-	V
Collector to emitter voltage	$V_{CE(ON)}$	$V_{GE} = 15\text{ V}, I_C = 60\text{ A}$	-	1.45	1.62	V
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}$	-	1.56	1.73	
		$V_{GE} = 15\text{ V}, I_C = 60\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.52	-	
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.67	-	
Gate threshold voltage	$V_{GE(th)}$	$V_{CE} = V_{GE}, I_C = 5.6\text{ mA}$	3.6	5.3	7.1	
Temperature coefficient of threshold voltage	$\Delta V_{GE(th)}/\Delta T_J$	$V_{CE} = V_{GE}, I_C = 1.4\text{ mA}$ ( $25\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$ )	-	-18	-	mV/ $^\circ\text{C}$
Forward transconductance	$g_{fe}$	$V_{CE} = 20\text{ V}, I_C = 75\text{ A}$	-	72	-	S
Transfer characteristics	$V_{GE}$	$V_{CE} = 20\text{ V}, I_C = 75\text{ A}$	-	8.3	-	V
Zero gate voltage collector current	$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 600\text{ V}$	-	0.0005	0.1	mA
		$V_{GE} = 0\text{ V}, V_{CE} = 600\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	0.065	-	
Gate to emitter leakage current	$I_{GES}$	$V_{GE} = \pm 20\text{ V}, V_{CE} = 0\text{ V}$	-	-	$\pm 400$	nA
<b>D5 - D6 CLAMPING DIODE</b>						
Cathode to anode blocking voltage	$V_{BR}$	$I_R = 100\text{ }\mu\text{A}$	600	-	-	V
Forward voltage drop	$V_{FM}$	$I_F = 40\text{ A}$	-	1.83	2.35	
		$I_F = 40\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.51	-	
Reverse leakage current	$I_{RM}$	$V_R = 600\text{ V}$	-	0.0002	0.1	mA
		$V_R = 600\text{ V}, T_J = 125\text{ }^\circ\text{C}$	-	0.028	-	
<b>D1 - D2 - D3 - D4 AP DIODE</b>						
Forward voltage drop	$V_{FM}$	$I_F = 30\text{ A}$	-	1.2	1.41	V
		$I_F = 30\text{ A}, T_J = 125\text{ }^\circ\text{C}$	-	1.06	-	



<b>SWITCHING CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>Q1 - Q4 IGBT (WITH D5 - D6 CLAMPING DIODE)</b>						
Total gate charge (turn-on)	$Q_g$	$I_C = 75\text{ A}$	-	150	-	nC
Gate to emitter charge (turn-on)	$Q_{ge}$	$V_{CC} = 400\text{ V}$	-	40	-	
Gate to collector charge (turn-on)	$Q_{gc}$	$V_{GE} = 15\text{ V}$	-	60	-	
Turn-on switching loss	$E_{ON}$	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}^{(1)}$	-	0.94	-	mJ
Turn-off switching loss	$E_{OFF}$		-	1.1	-	
Total switching loss	$E_{TOT}$		-	2.04	-	
Turn-on delay time	$t_{d(on)}$		-	78	-	ns
Rise time	$t_r$		-	72	-	
Turn-off delay time	$t_{d(off)}$	-	101	-		
Fall time	$t_f$	-	65	-		
Turn-on switching loss	$E_{ON}$	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	1.13	-	mJ
Turn-off switching loss	$E_{OFF}$		-	1.61	-	
Total switching loss	$E_{TOT}$		-	2.74	-	
Turn-on delay time	$t_{d(on)}$		-	78	-	ns
Rise time	$t_r$		-	72	-	
Turn-off delay time	$t_{d(off)}$	-	106	-		
Fall time	$t_f$	-	107	-		
Input capacitance	$C_{ies}$	$V_{GE} = 0\text{ V}$	-	4440	-	pF
Output capacitance	$C_{oes}$	$V_{CC} = 30\text{ V}$	-	245	-	
Reverse transfer capacitance	$C_{res}$	$f = 1\text{ MHz}$	-	130	-	
Reverse bias safe operating area	RBSOA	$T_J = 175\text{ }^\circ\text{C}$ , $I_C = 200\text{ A}$ $V_{CC} = 300\text{ V}$ , $V_P = 600\text{ V}$ $R_g = 4.7\text{ }\Omega$ , $V_{GE} = 15\text{ V to }0\text{ V}$	Fullsquare			
Short circuit safe operating area	SCSOA	$R_g = 10\text{ }\Omega$ , $V_{CC} = 400\text{ V}$ , $V_P = 600\text{ V}$ $V_{GE} = 15\text{ V to }0$	-	-	5	$\mu\text{s}$
<b>Q2 - Q3 IGBT (WITH FREEWHEELING EXTERNAL TO-247 DIODE DISCRETE 30ETH06)</b>						
Total gate charge (turn-on)	$Q_g$	$I_C = 120\text{ A}$	-	240	-	nC
Gate to emitter charge (turn-on)	$Q_{ge}$	$V_{CC} = 400\text{ V}$	-	69	-	
Gate to collector charge (turn-on)	$Q_{gc}$	$V_{GE} = 15\text{ V}$	-	90	-	
Turn-on switching loss	$E_{ON}$	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}^{(1)}$	-	0.85	-	mJ
Turn-off switching loss	$E_{OFF}$		-	1.54	-	
Total switching loss	$E_{TOT}$		-	2.39	-	
Turn-on delay time	$t_{d(on)}$		-	111	-	ns
Rise time	$t_r$		-	81	-	
Turn-off delay time	$t_{d(off)}$	-	130	-		
Fall time	$t_f$	-	74	-		
Turn-on switching loss	$E_{ON}$	$I_C = 75\text{ A}$ $V_{CC} = 300\text{ V}$ $V_{GE} = 15\text{ V}$ $R_g = 4.7\text{ }\Omega$ $L = 500\text{ }\mu\text{H}$ $T_J = 125\text{ }^\circ\text{C}^{(1)}$	-	1.0	-	mJ
Turn-off switching loss	$E_{OFF}$		-	1.83	-	
Total switching loss	$E_{TOT}$		-	2.83	-	
Turn-on delay time	$t_{d(on)}$		-	111	-	ns
Rise time	$t_r$		-	83	-	
Turn-off delay time	$t_{d(off)}$	-	140	-		
Fall time	$t_f$	-	104	-		
Input capacitance	$C_{ies}$	$V_{GE} = 0\text{ V}$	-	7750	-	pF
Output capacitance	$C_{oes}$	$V_{CC} = 30\text{ V}$	-	550	-	
Reverse transfer capacitance	$C_{res}$	$f = 1\text{ MHz}$	-	225	-	
Reverse bias safe operating area	RBSOA	$T_J = 175\text{ }^\circ\text{C}$ , $I_C = 250\text{ A}$ $V_{CC} = 300\text{ V}$ , $V_P = 600\text{ V}$ $R_g = 4.7\text{ }\Omega$ , $V_{GE} = 15\text{ V to }0\text{ V}$	Fullsquare			
Short circuit safe operating area	SCSOA	$R_g = 10\text{ }\Omega$ , $V_{CC} = 400\text{ V}$ , $V_P = 600\text{ V}$ $V_{GE} = 15\text{ V to }0$	-	-	5	$\mu\text{s}$



<b>SWITCHING CHARACTERISTICS</b> ( $T_J = 25\text{ }^\circ\text{C}$ unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
<b>D5 - D6 CLAMPING DIODE</b>						
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$	-	59	-	ns
Diode peak reverse current	$I_{rr}$	$I_F = 50\text{ A}$	-	8.5	-	A
Diode recovery charge	$Q_{rr}$	$di/dt = 500\text{ A}/\mu\text{s}$	-	257	-	nC
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$	-	110	-	ns
Diode peak reverse current	$I_{rr}$	$I_F = 50\text{ A}$	-	18.5	-	A
Diode recovery charge	$Q_{rr}$	$di/dt = 500\text{ A}/\mu\text{s}$ , $T_J = 125\text{ }^\circ\text{C}$	-	1020	-	nC
<b>D1 - D2 - D3 - D4 AP DIODE</b>						
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$	-	108	-	ns
Diode peak reverse current	$I_{rr}$	$I_F = 50\text{ A}$	-	19.5	-	A
Diode recovery charge	$Q_{rr}$	$di/dt = 500\text{ A}/\mu\text{s}$	-	1062	-	nC
Diode reverse recovery time	$t_{rr}$	$V_R = 200\text{ V}$	-	174	-	ns
Diode peak reverse current	$I_{rr}$	$I_F = 50\text{ A}$	-	31	-	A
Diode recovery charge	$Q_{rr}$	$di/dt = 500\text{ A}/\mu\text{s}$ , $T_J = 125\text{ }^\circ\text{C}$	-	2716	-	nC

**Note**

(1) Energy losses include "tail" and diode reverse recovery.

<b>INTERNAL NTC - THERMISTOR SPECIFICATIONS</b>				
PARAMETER	SYMBOL	TEST CONDITIONS	TYP.	UNITS
Resistance	$R_{25}$	$T_J = 25\text{ }^\circ\text{C}$	$5000 \pm 5\%$	$\Omega$
	$R_{125}$	$T_J = 125\text{ }^\circ\text{C}$	$493 \pm 5\%$	
B-constant	B	$R_2 = R_1 e^{[B(1/T_2 - 1/T_1)]}$	$3375 \pm 5\%$	K
Temperature range			-40 to 125	$^\circ\text{C}$
Maximum operating temperature			220	
Dissipation constant			2	mW/ $^\circ\text{C}$
Thermal time constant			8	s

<b>THERMAL AND MECHANICAL SPECIFICATIONS</b>					
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNITS
Q1 - Q4 IGBT - Junction to case thermal resistance (per switch)	$R_{thJC}$	-	-	0.51	$^\circ\text{C}/\text{W}$
Q2 - Q3 IGBT - Junction to case thermal resistance (per switch)		-	-	0.37	
D5 - D6 Clamping diode - Junction to case thermal resistance (per diode)		-	-	0.86	
D1 - D2 - D3 - D4 AP diode - Junction to case thermal resistance (per diode)		-	-	1.4	
Q1 - Q4 IGBT - Case to sink thermal resistance (per switch)	$R_{thCS}^{(1)}$	-	0.84	-	
Q2 - Q3 IGBT - Case to sink thermal resistance (per switch)		-	0.8	-	
D5 - D6 Clamping diode - Case to sink thermal resistance (per diode)		-	1.16	-	
D1 - D2 - D3 - D4 AP diode - Case to sink thermal resistance (per diode)		-	1.12	-	
Case to sink thermal resistance per module		-	0.1	-	$^\circ\text{C}/\text{W}$
Mounting torque (M4)		2	-	3	Nm
Weight		-	45	-	g

**Note**

(1) Mounting surface flat, smooth, and greased

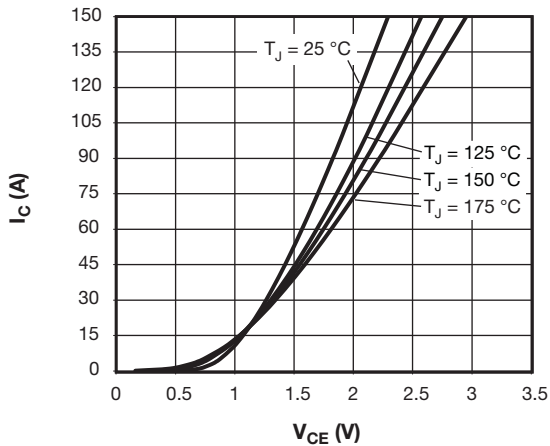


Fig. 1 - Typical Q1 - Q4 Trench IGBT Output Characteristics  
 $V_{GE} = 15\text{ V}$

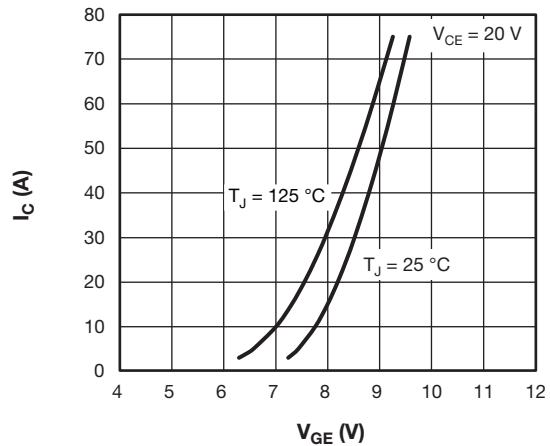


Fig. 4 - Typical Q1 - Q4 Trench IGBT Transfer Characteristics

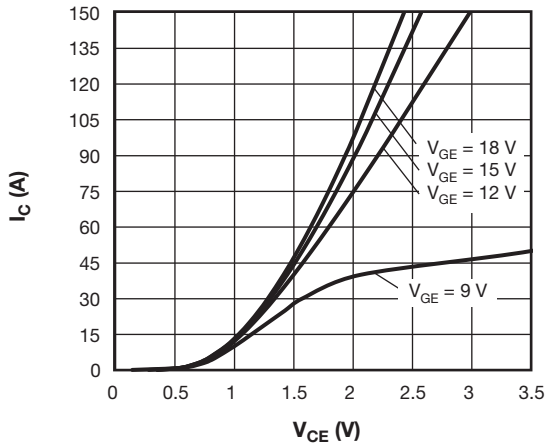


Fig. 2 - Typical Q1 - Q4 Trench IGBT Output Characteristics  
 $T_J = 125\text{ °C}$

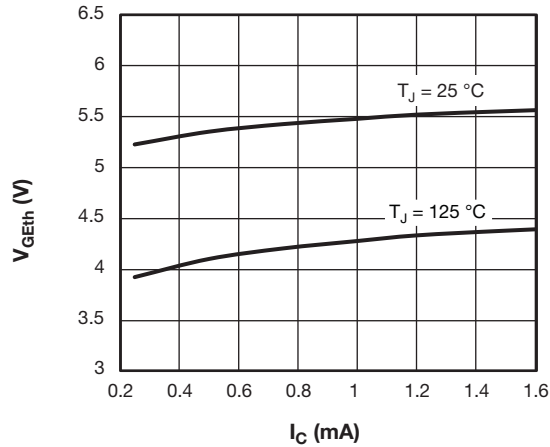


Fig. 5 - Typical Q1 - Q4 Trench IGBT Gate Threshold Voltage

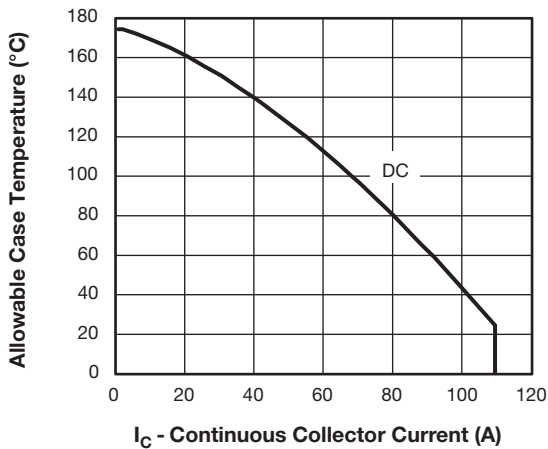


Fig. 3 - Maximum Q1 - Q4 Trench IGBT Continuous Collector Current vs. Case Temperature

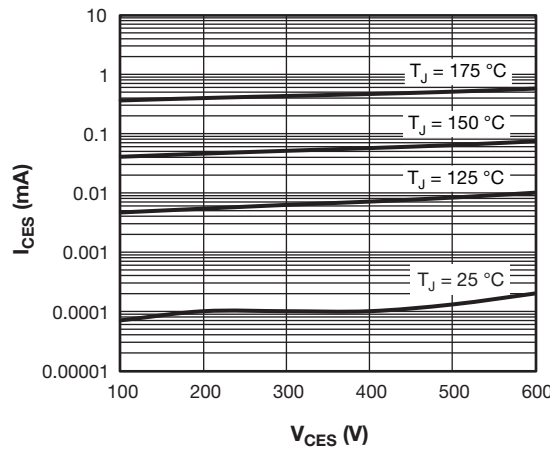


Fig. 6 - Typical Q1 - Q4 Trench IGBT Zero Gate Voltage Collector Current

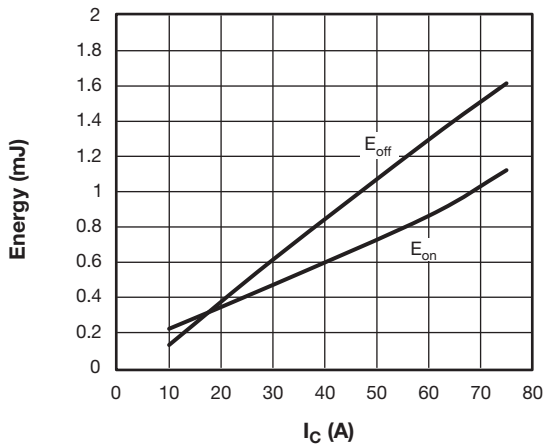


Fig. 7 - Typical Q1 - Q4 Trench IGBT Energy Loss vs.  $I_C$  (with D5 - D6 Clamping Diode)  
 $T_J = 125^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $R_g = 4.7\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

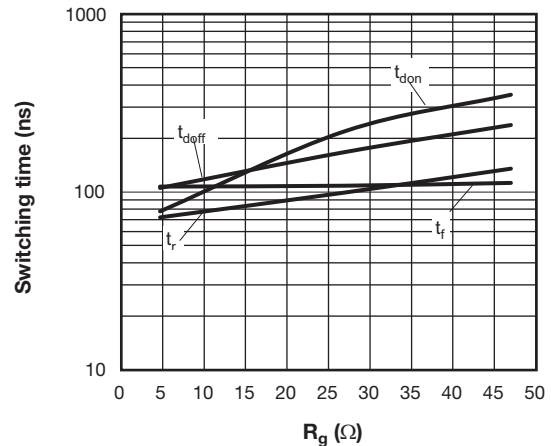


Fig. 10 - Typical Q1 - Q4 Trench IGBT Switching Time vs.  $R_g$  (with D5 - D6 Clamping Diode)  
 $T_J = 125^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $I_C = 75\text{ A}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

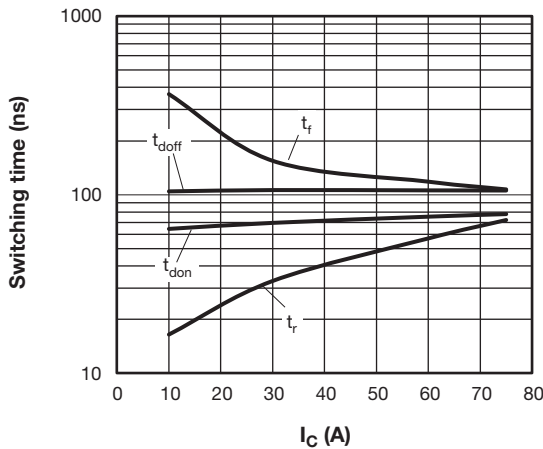


Fig. 8 - Typical Q1 - Q4 Trench IGBT Switching Loss vs.  $I_C$  (with D5 - D6 Clamping Diode)  
 $T_J = 125^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $R_g = 4.7\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

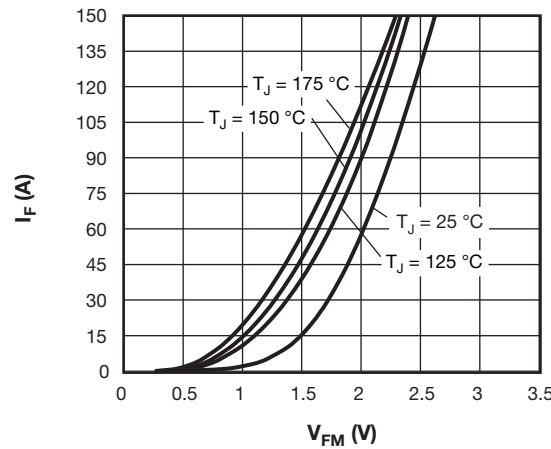


Fig. 11 - Typical D5 - D6 Clamping Diode Forward Characteristics

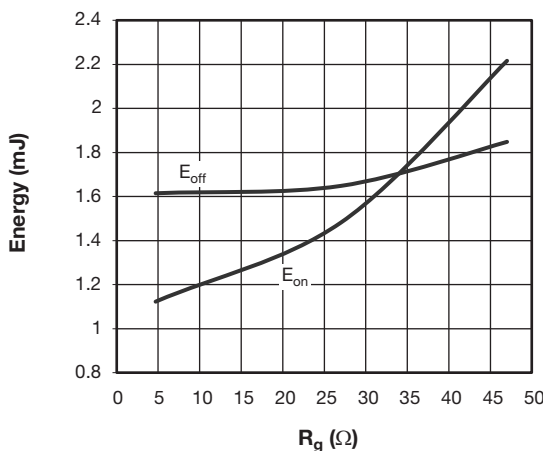


Fig. 9 - Typical Q1 - Q4 Trench IGBT Energy Loss vs.  $R_g$  (with D5 - D6 Clamping Diode)  
 $T_J = 125^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $I_C = 75\text{ A}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

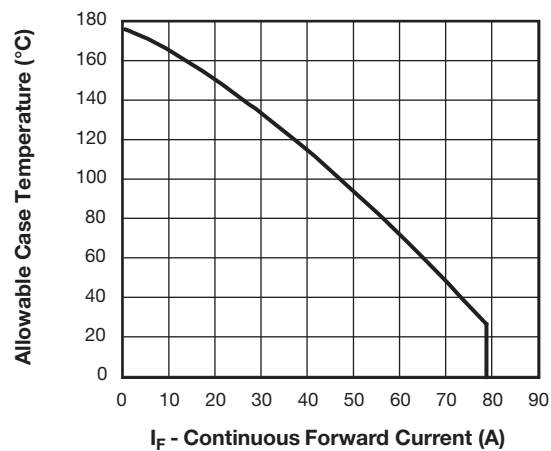


Fig. 12 - Maximum D5 - D6 Clamping Diode Forward Current vs. Case Temperature

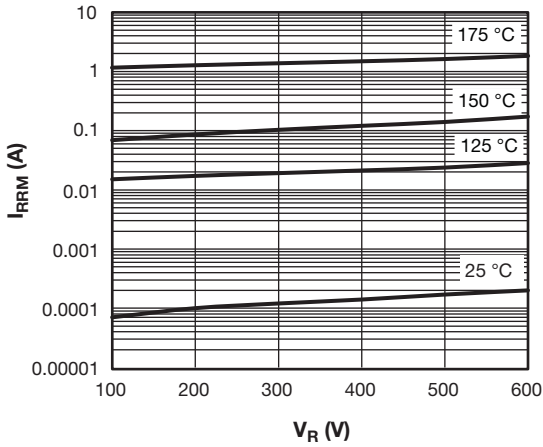


Fig. 13 - Typical D5 - D6 Clamping Diode Reverse Leakage Current

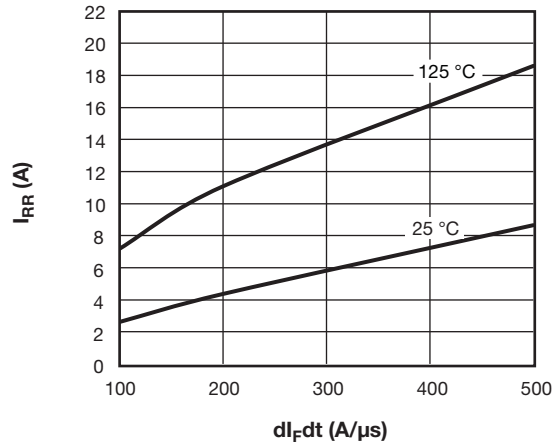


Fig. 15 - Typical D5 - D6 Clamping Diode Reverse Recovery Current vs.  $di_F/dt$ ,  $V_{Rr} = 200\text{ V}$ ,  $I_F = 50\text{ A}$

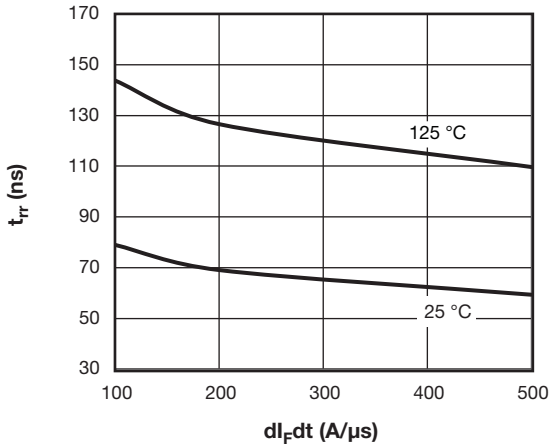


Fig. 14 - Typical D5 - D6 Clamping Diode Reverse Recovery Time vs.  $di_F/dt$ ,  $V_{Rr} = 200\text{ V}$ ,  $I_F = 50\text{ A}$

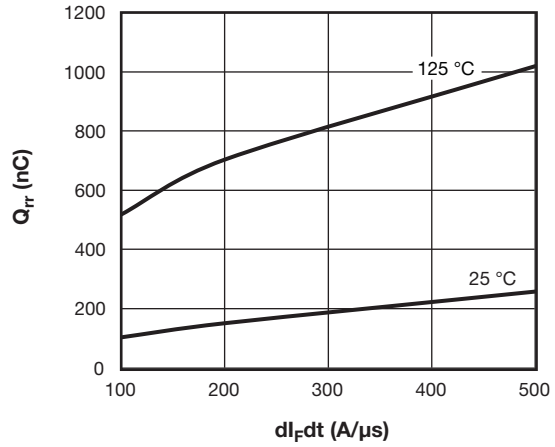


Fig. 16 - Typical D5 - D6 Clamping Diode Reverse Recovery Charge vs.  $di_F/dt$ ,  $V_{Rr} = 200\text{ V}$ ,  $I_F = 50\text{ A}$

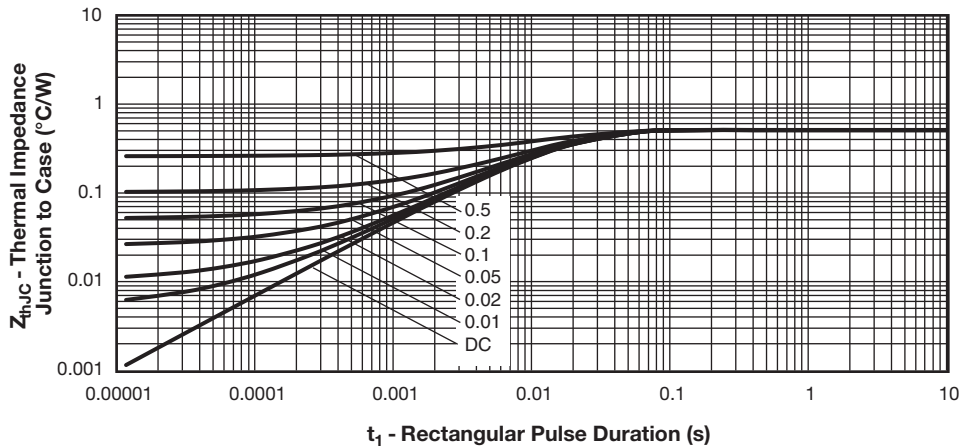


Fig. 17 - Maximum Thermal Impedance  $Z_{thJc}$  Characteristics (Q1 - Q4 Trench IGBT)



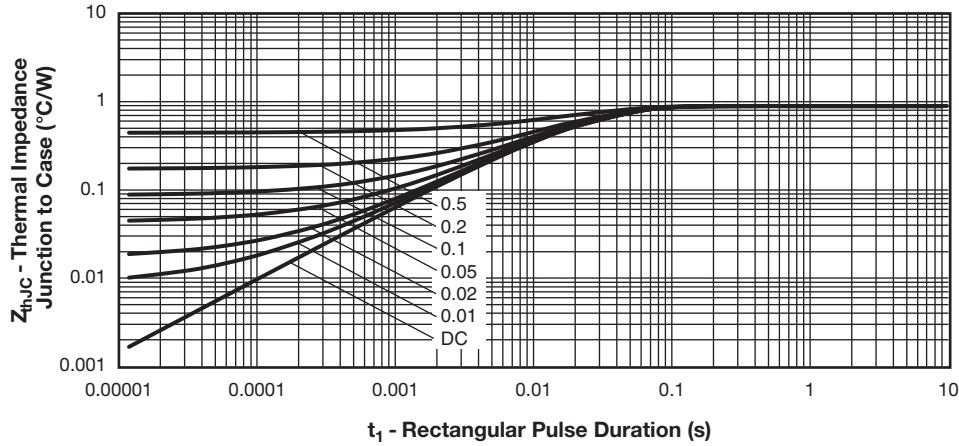


Fig. 18 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (D5 - D6 Clamping Diode)

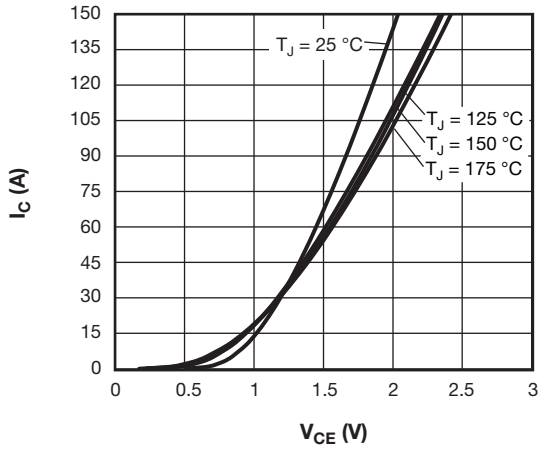


Fig. 19 - Typical Q2 - Q3 Trench IGBT Output Characteristics  
 $V_{GE} = 15\text{ V}$

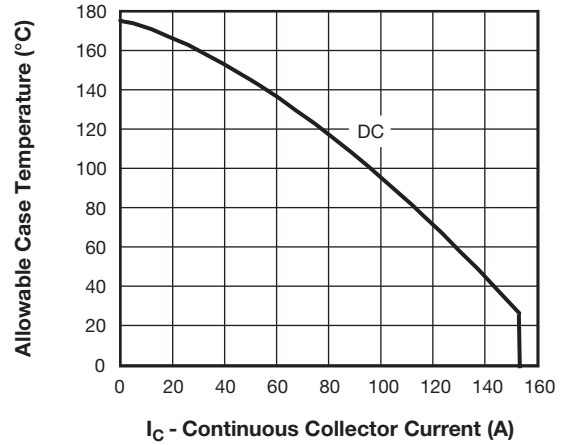


Fig. 21 - Maximum Q2 - Q3 Trench IGBT Continuous Collector Current vs. Case Temperature

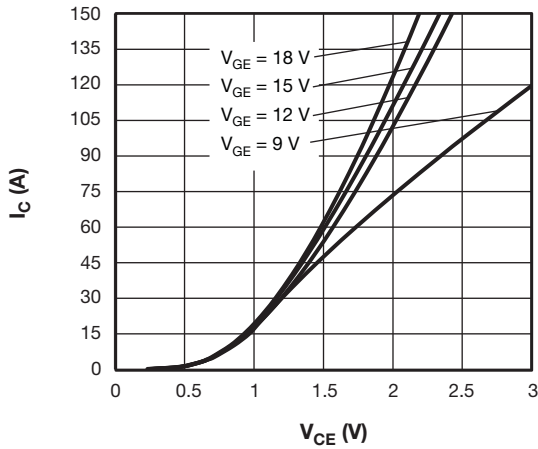


Fig. 20 - Typical Q2 - Q3 Trench IGBT Output Characteristics  
 $T_J = 125\text{ °C}$

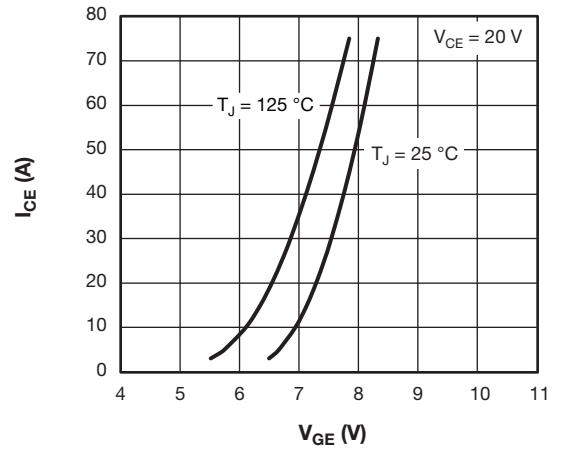


Fig. 22 - Typical Q2 - Q3 Trench IGBT Transfer Characteristics

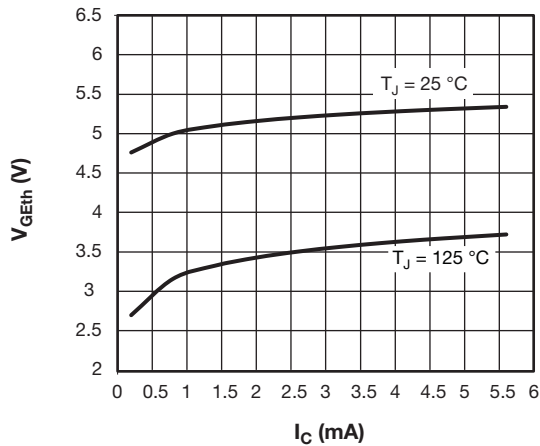


Fig. 23 - Typical Q2 - Q3 Trench IGBT Gate Threshold Voltage

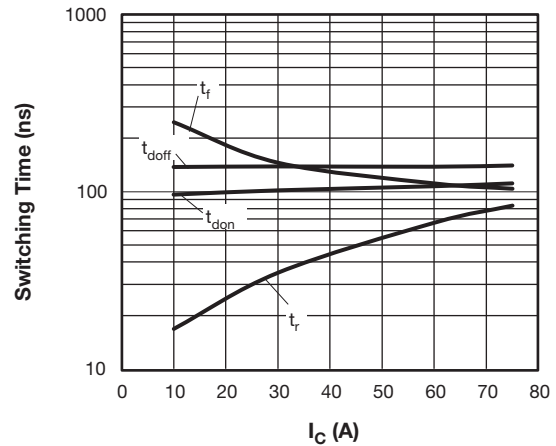


Fig. 26 - Typical Q2 - Q3 Trench IGBT Switching Time vs.  $I_C$  (with Freewheeling External TO-247 Diode Discrete 30ETH06),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $R_g = 4.7\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

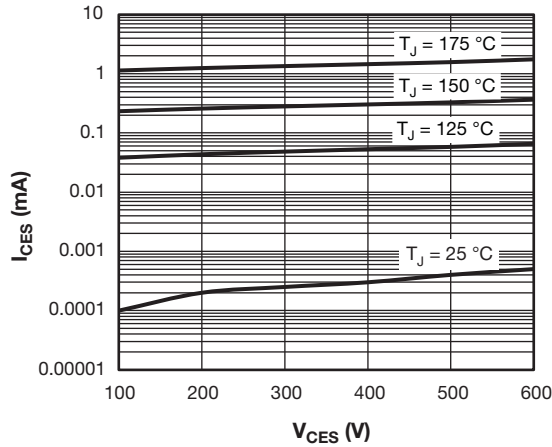


Fig. 24 - Typical Q2 - Q3 Trench IGBT Zero Gate Voltage Collector Current

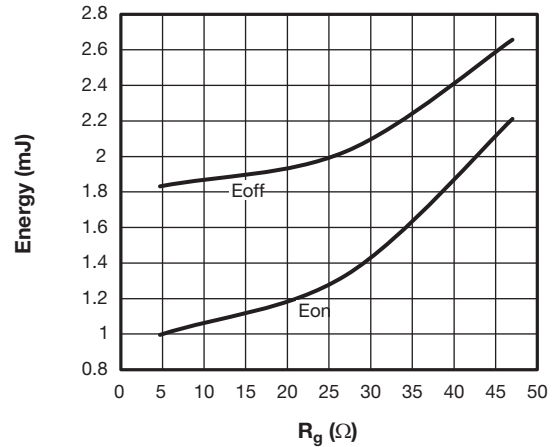


Fig. 27 - Typical Q2 - Q3 Trench IGBT Energy Loss vs.  $R_g$  (with Freewheeling External TO-247 Diode Discrete 30ETH06),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $I_C = 75\text{ A}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

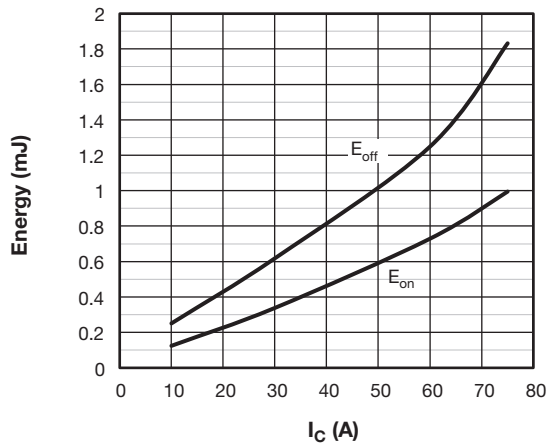


Fig. 25 - Typical Q2 - Q3 Trench IGBT Energy Loss vs.  $I_C$  (with Freewheeling External TO-247 Diode Discrete 30ETH06),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $R_g = 4.7\ \Omega$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

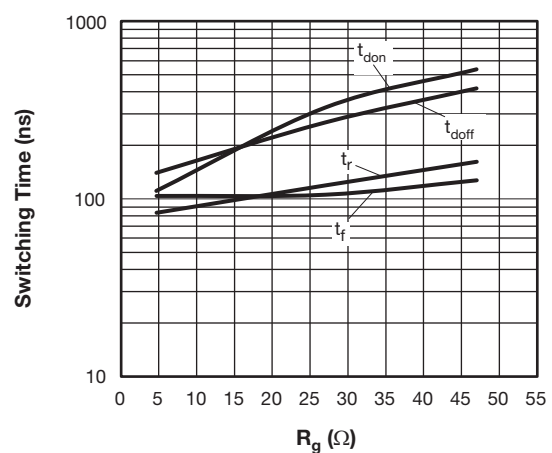


Fig. 28 - Typical Q2 - Q3 Trench IGBT Switching Time vs.  $R_g$  (with Freewheeling External TO-247 Diode Discrete 30ETH06),  $T_J = 125\text{ }^\circ\text{C}$ ,  $V_{CC} = 300\text{ V}$ ,  $I_C = 75\text{ A}$ ,  $V_{GE} = 15\text{ V}$ ,  $L = 500\ \mu\text{H}$

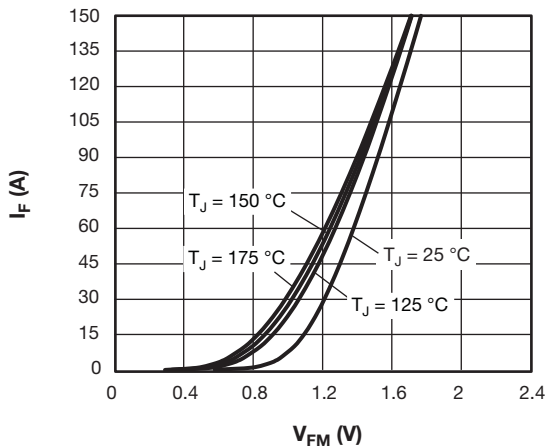


Fig. 29 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Forward Characteristics

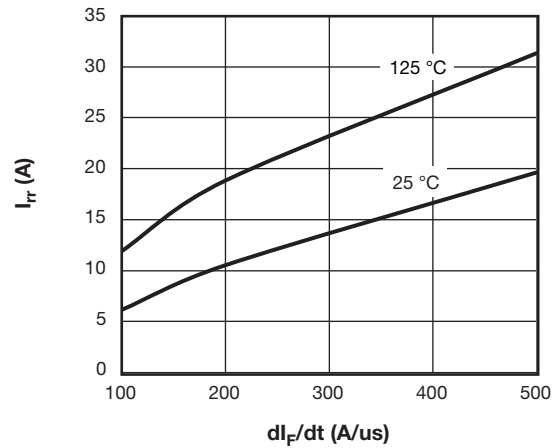


Fig. 32 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Reverse Recovery Current vs.  $dI_F/dt$   
 $V_{rr} = 200\text{ V}$ ,  $I_F = 50\text{ A}$

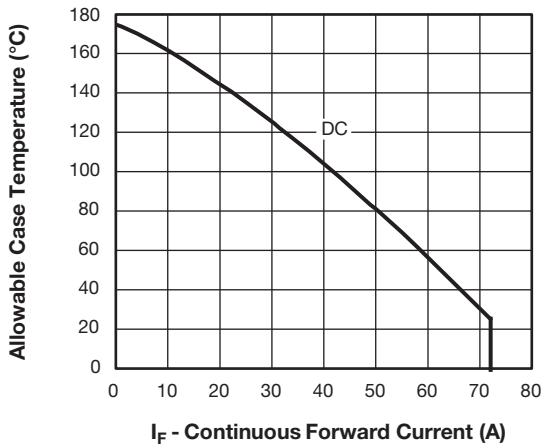


Fig. 30 - Maximum D1 - D2 - D3 - D4 Antiparallel Diode Forward Current vs. Case Temperature

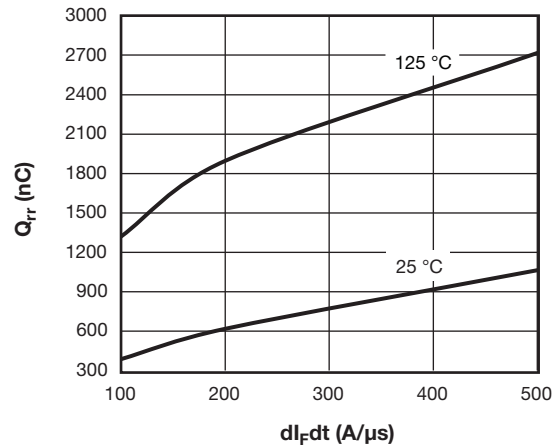


Fig. 33 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Reverse Recovery Charge vs.  $dI_F/dt$   
 $V_{rr} = 200\text{ V}$ ,  $I_F = 50\text{ A}$

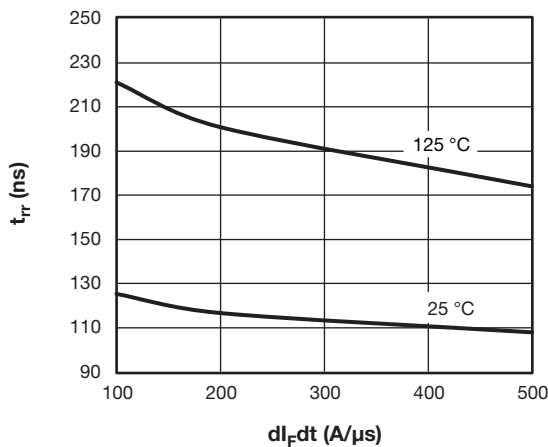


Fig. 31 - Typical D1 - D2 - D3 - D4 Antiparallel Diode Reverse Recovery Time vs.  $dI_F/dt$   
 $V_{rr} = 200\text{ V}$ ,  $I_F = 50\text{ A}$

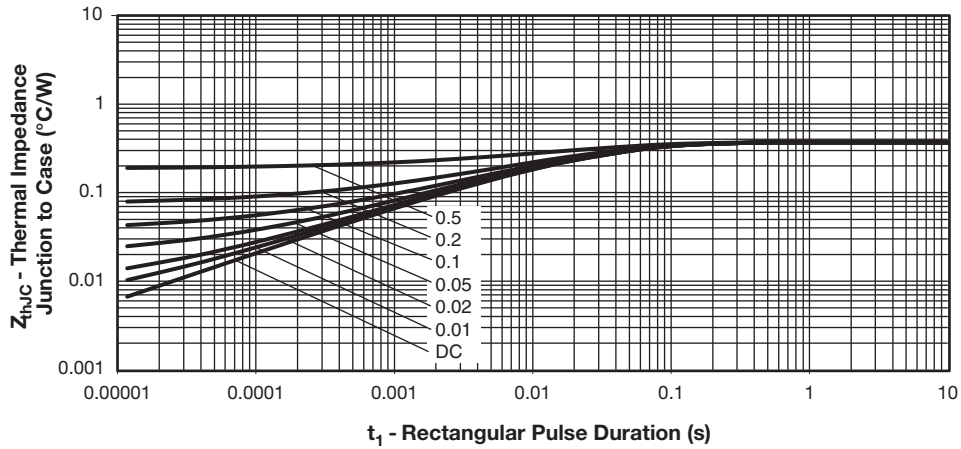


Fig. 34 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (Q2 - Q3 Trench IGBT)

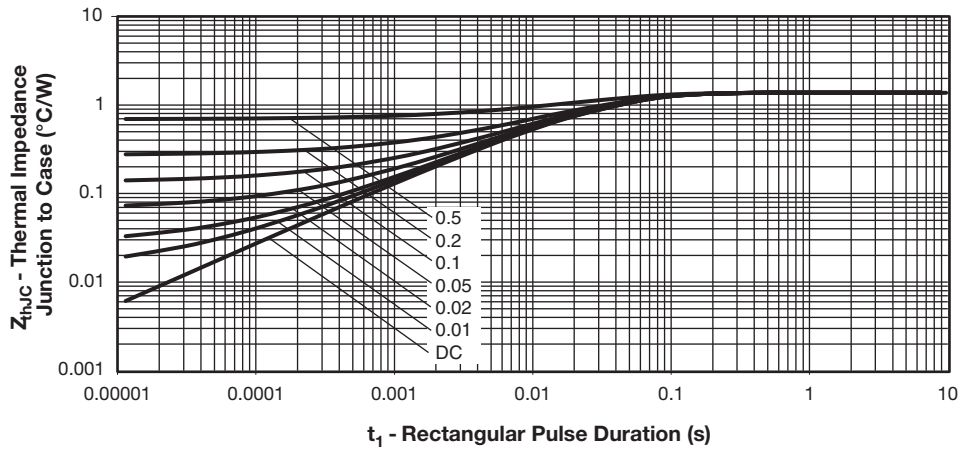


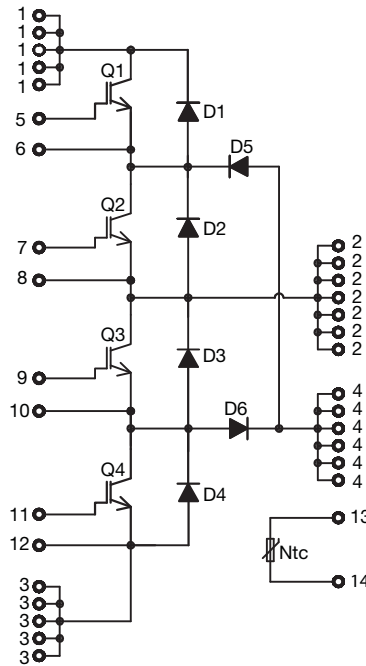
Fig. 35 - Maximum Thermal Impedance  $Z_{thJC}$  Characteristics (D1 - D2 - D3 - D4 Antiparallel Diode)

**ORDERING INFORMATION TABLE**

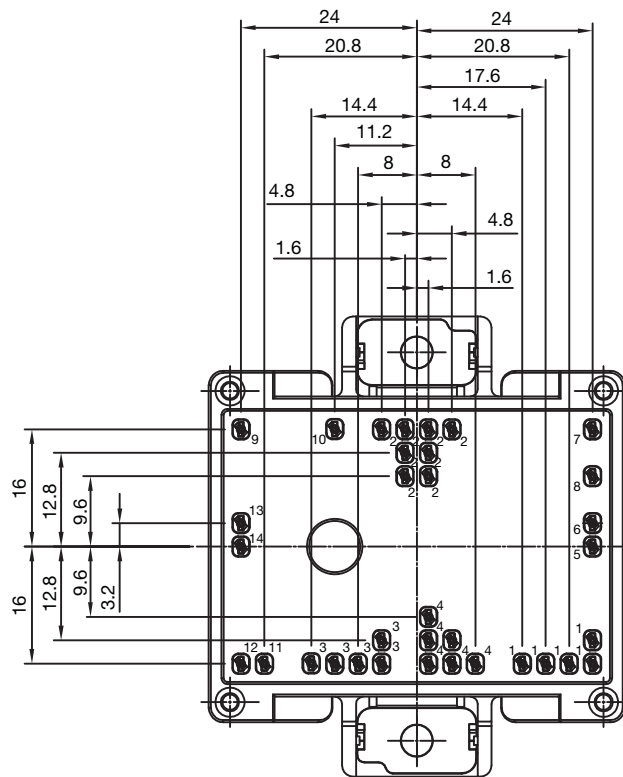
Device code	<b>VS-</b>	<b>ET</b>	<b>F</b>	<b>075</b>	<b>Y</b>	<b>60</b>	<b>U</b>
	①	②	③	④	⑤	⑥	⑦

- 1** - Vishay Semiconductors product
- 2** - Package indicator (ET = EMIPAK-2B)
- 3** - Circuit configuration (F = 3-levels half-bridge inverter stage)
- 4** - Current rating (075 = 75 A)
- 5** - Switch die technology (Y = Trench IGBT)
- 6** - Voltage rating (60 = 600 V)
- 7** - Diode die technology (U = Ultrafast diode)

**CIRCUIT CONFIGURATION**



**PACKAGE**

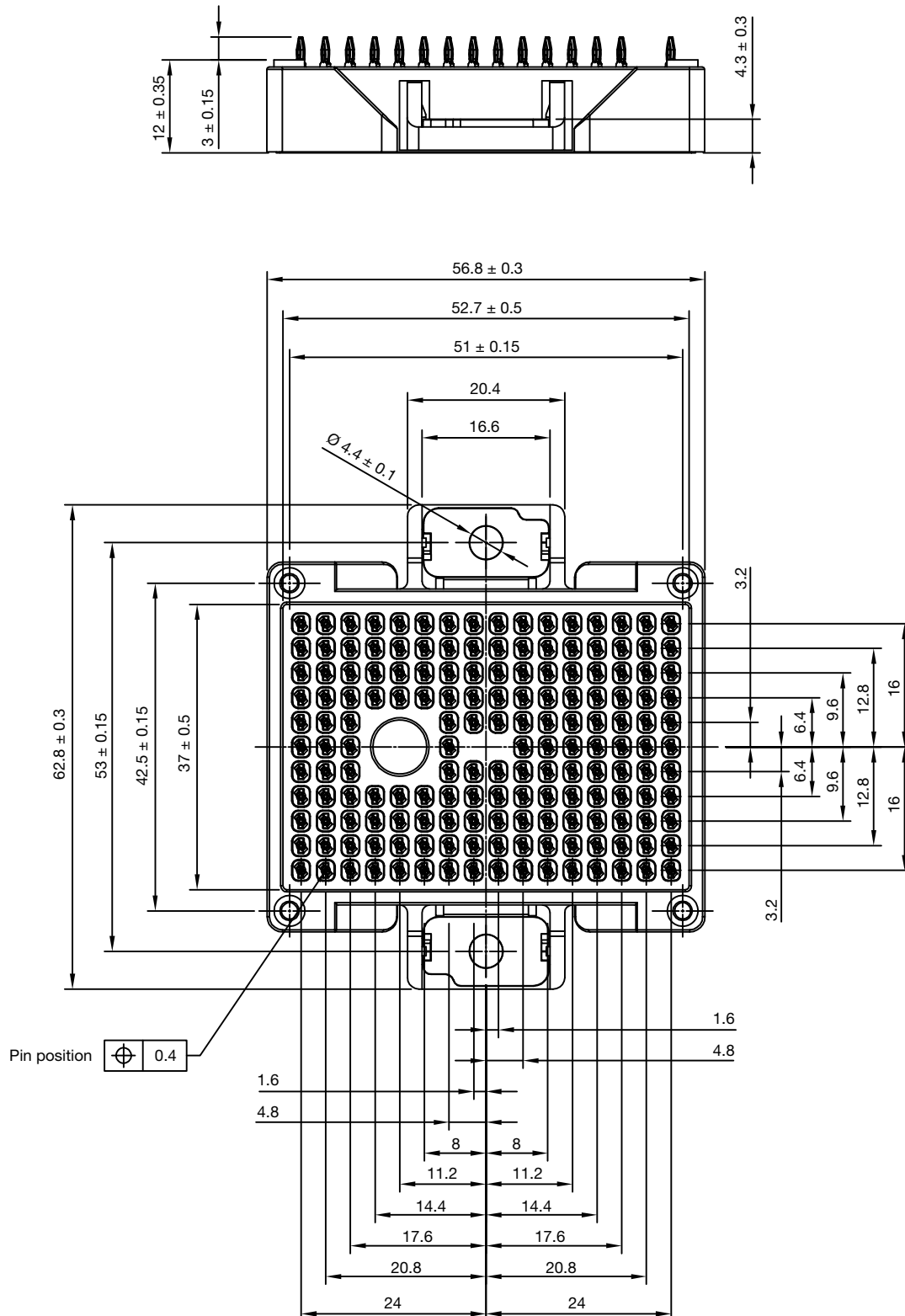


LINKS TO RELATED DOCUMENTS	
Dimensions	<a href="http://www.vishay.com/doc?95559">www.vishay.com/doc?95559</a>



## EMIPAK-2B PressFit

**DIMENSIONS** in millimeters





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**Please note that some Vishay documentation may still make reference to RoHS Directive 2002/95/EC. We confirm that all the products identified as being compliant to Directive 2002/95/EC conform to Directive 2011/65/EU.**

**Vishay Intertechnology, Inc. hereby certifies that all its products that are identified as Halogen-Free follow Halogen-Free requirements as per JEDEC JS709A standards. Please note that some Vishay documentation may still make reference to the IEC 61249-2-21 definition. We confirm that all the products identified as being compliant to IEC 61249-2-21 conform to JEDEC JS709A standards.**



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- Оперативные поставки широкого спектра электронных компонентов отечественного и импортного производства напрямую от производителей и с крупнейших мировых складов;
- Поставка более 17-ти миллионов наименований электронных компонентов;
- Поставка сложных, дефицитных, либо снятых с производства позиций;
- Оперативные сроки поставки под заказ (от 5 рабочих дней);
- Экспресс доставка в любую точку России;
- Техническая поддержка проекта, помощь в подборе аналогов, поставка прототипов;
- Система менеджмента качества сертифицирована по Международному стандарту ISO 9001;
- Лицензия ФСБ на осуществление работ с использованием сведений, составляющих государственную тайну;
- Поставка специализированных компонентов (Xilinx, Altera, Analog Devices, Intersil, Interpoint, Microsemi, Aeroflex, Peregrine, Syfer, Eurofarad, Texas Instrument, Miteq, Cobham, E2V, MA-COM, Hittite, Mini-Circuits, General Dynamics и др.);

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- Подбор оптимального решения, техническое обоснование при выборе компонента;
- Подбор аналогов;
- Консультации по применению компонента;
- Поставка образцов и прототипов;
- Техническая поддержка проекта;
- Защита от снятия компонента с производства.



#### Как с нами связаться

**Телефон:** 8 (812) 309 58 32 (многоканальный)

**Факс:** 8 (812) 320-02-42

**Электронная почта:** [org@eplast1.ru](mailto:org@eplast1.ru)

**Адрес:** 198099, г. Санкт-Петербург, ул. Калинина, дом 2, корпус 4, литера А.